CD contour measuring station 140AF, Type: CD140AF

Order data

Order number	499299 CD140AF
GTIN	
Item class	40W

Description

Version:
The MarSurf CD 140 A has a touch probe system with a measurement range of up to 70 mm, and the stylus tips can be changed quickly and without the need for any tools – all without recalibration.
Application:
The computer-aided measuring station permits comprehensive and quick evaluation of the measurement results:

- **Comprehensive contour measurement functions, fast and simple**
- **Stylus tips can be changed without the need for tools**
- **Traversing velocity in X axis of up to 200 mm/s**
- **Simple creation of programs or individual measurements with MarWin**
- **Automatic evaluation, best contour fit, CAD contour comparison and many more.**
- **Can optionally be expanded with roughness measurement feature (Rz > 2 µm)**
- **Measurements with double stylus tip are possible**
- **Flexible mounting plate with 25 mm hole grid, no additional X/Y table required**

Supplied with:
Contour measuring machine, machine base incl. Y adjustment, PG A 36-350-25 contact element, MarWin EasyContour plus mobile software, contour calibration standard with 2 balls (45 mm and 6 mm).
Optional extras:
PC

Technical description

Height	426 mm
Traverse path X	140 mm
Contact point length	350 mm
Gauging force	4 - 30 mN
Guide deviation Z	1 (over 140 mm) µm
Depth	385 mm
Resolution	19 nm
Measuring speed X	0.1 - 10 mm/s
Width	836 mm
Positioning speed in X	1 - 200 mm/s
Measuring range Z	70 mm
Type of product	Contour measurement bench